



# IEEE SW Test Workshop

## Semiconductor Wafer Test Workshop

June 7-10, 2009 - Paradise Point Resort - San Diego, CA

### PROGRAM OVERVIEW

The 19th annual SW Test Workshop is the only IEEE-sponsored conference that focuses on all aspects of semiconductor wafer and die level probe testing. The workshop begins Sunday afternoon, June 7, with a tutorial and three presentations that discuss aspects of controlling bond pad and probe card damage, followed by a welcome reception, dinner, and a Keynote Speaker. The Technical Program begins Monday morning with 30-minute presentations in theme-oriented sessions. Advanced registration is \$580 for IEEE members and \$700 for non-members, and includes all meals, refreshments, social activities, and conference and exhibit attendance, as well as the printed Proceedings distributed at the Workshop. The workshop concludes Wednesday at Noon, June 10, after the awards presentation and luncheon. To receive the advance registration discount, register online at [www.swtest.org](http://www.swtest.org)

Registration deadline is **May 15, 2009**. On site registration will be \$680 for members and \$800 for non-members.

**Keynote Address:** The Keynote Presentation will be made on the Sunday night after the welcome reception. The presentation will include a wide range of relevant topics of interest not only to wafer sort, but to the semiconductor industry as a whole. In the past, industry luminaries and technologists from Verigy, Intel, Qualcomm, and FormFactor give outstanding presentations that were thought provoking, timely and even controversial.

#### Technical Program Sessions:

- ▶ Probe "Year in Review"
- ▶ MEMS for Production-Level Probing
- ▶ Advances in Traditional Probe Card Technologies
- ▶ Improving Test Cell Performance
- ▶ Power and High Voltage
- ▶ Large Array Probing
- ▶ Probe Potpourri
- ▶ Probe Card Cleaning Practices
- ▶ Strategic Design Methodologies
- ▶ Probe Challenges

The complete technical program with presentation times, titles, and presenters will be on the web site: [www.swtest.org](http://www.swtest.org). The schedule and session titles are subject to change without notice.

**Bond Pad Damage Tutorial:** On Sunday afternoon a tutorial will be held which will give new technologists insights for the problems facing the wafer test industry. Experienced technologists will find the tutorial session a great way to revisit many of the issues that they have faced in the past. The information presented will include many key research findings from the probe and assembly industries from the last decade. After the tutorial, technical sessions related to the tutorial will be presented to discuss current practices for the wafer sort environment.

**EXPO Exhibits (EXPO - 2009)** Fifty-three of the top probe card, probe equipment, and related service suppliers will exhibit the latest products, EXPO viewing hours do not compete with the Technical Program. The EXPO will be open for three hours on Monday evening, June 8, and will include a variety of carving stations for dinner. The EXPO will be open for two hours on Tuesday afternoon, June 9, and will include afternoon refreshments. It's the only conference where ALL the top probe and probe-related suppliers are in one place at one time.

**Social Activities:** SWTW is a probe technology forum with a relaxed atmosphere held at a beautiful resort hotel and has ample time dedicated to informal discussions and networking. This year's special social activities a Casino Night at the Resort. Dinner will begin at 6:00 PM with the tables opening for play at 7:00 PM going until the closing raffles at 10:00 PM. It's fun times with fun money for all!

**Hotel reservations must be made separately.** Contact the Paradise Point Resort and Spa at (800) 344-2626 or via the room reservations web site link available at [www.swtest.org](http://www.swtest.org) to get a discount rate of \$199 per night. When placing your reservation by phone reference **SWTW 2009**. Contact the SWTW office at +1.540.937.5066 for alternate hotels.

The Semiconductor Wafer Test Workshop is sponsored by the IEEE Components, Packaging, and Manufacturing Technology Society



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